

# DS1249W 3.3V 2048kb Nonvolatile SRAM

#### www.maxim-ic.com

### **FEATURES**

- 10 years minimum data retention in the absence of external power
- Data is automatically protected during power loss
- Unlimited write cycles
- Low-power CMOS operation
- Read and write access times of 100ns
- Lithium energy source is electrically disconnected to retain freshness until power is applied for the first time
- Optional industrial (IND) temperature range of -40°C to +85°C
- JEDEC standard 32-pin DIP package

### PIN ASSIGNMENT

| NC  | 1  | 32 | V <sub>cc</sub> |
|-----|----|----|-----------------|
| A16 | 2  | 31 | A15             |
| A14 | 3  | 30 | A17             |
| A12 | 4  | 29 | WE              |
| A7  | 5  | 28 | A13             |
| A6  | 6  | 27 | A8              |
| A5  | 7  | 26 | A9              |
| A4  | 8  | 25 | <u>A11</u>      |
| A3  | 9  | 24 | OE              |
| A2  | 10 | 23 | <u>A10</u>      |
| A1  | 11 | 22 | CE              |
| A0  | 12 | 21 | DQ7             |
| DQ0 | 13 | 20 | DQ6             |
| DQ1 | 14 | 19 | DQ5             |
| DQ2 | 15 | 18 | DQ4             |
| GND | 16 | 17 | DQ3             |
|     |    |    |                 |

32-Pin Encapsulated Package 740mil Extended

### **PIN DESCRIPTION**

| - Address Inputs   |
|--------------------|
| - Data In/Data Out |
| - Chip Enable      |
| - Write Enable     |
| - Output Enable    |
| - Power (+3.3V)    |
| - Ground           |
| - No Connect       |
|                    |

### DESCRIPTION

The DS1249W 2048kb nonvolatile (NV) SRAMs are 2,097,152-bit, fully static, NV SRAMs organized as 262,144 words by 8 bits. Each NV SRAM has a self-contained lithium energy source and control circuitry that constantly monitors  $V_{CC}$  for an out-of-tolerance condition. When such a condition occurs, the lithium energy source is automatically switched on and write protection is unconditionally enabled to prevent data corruption. There is no limit on the number of write cycles that can be executed, and no additional support circuitry is required for microprocessor interfacing.

## **READ MODE**

The DS1249 devices execute a read cycle whenever  $\overline{WE}$  (Write Enable) is inactive (high) and  $\overline{CE}$  (Chip Enable) and  $\overline{OE}$  (Output Enable) are active (low). The unique address specified by the 18 address inputs  $(A_0 - A_{17})$  defines which of the 262,144 bytes of data is accessed. Valid data will be available to the eight data output drivers within  $t_{ACC}$  (Access Time) after the last address input signal is stable, providing that  $\overline{CE}$  and  $\overline{OE}$  access times are also satisfied. If  $\overline{OE}$  and  $\overline{CE}$  access times are not satisfied, then data access must be measured from the later-occurring signal ( $\overline{CE}$  or  $\overline{OE}$ ) and the limiting parameter is either  $t_{CO}$  for  $\overline{CE}$  or  $t_{OE}$  for  $\overline{OE}$  rather than  $t_{ACC}$ .

## WRITE MODE

The DS1249 executes a write cycle whenever the  $\overline{WE}$  and  $\overline{CE}$  signals are active (low) after address inputs are stable. The later-occurring falling edge of  $\overline{CE}$  or  $\overline{WE}$  will determine the start of the write cycle. The write cycle is terminated by the earlier rising edge of  $\overline{CE}$  or  $\overline{WE}$ . All address inputs must be kept valid throughout the write cycle.  $\overline{WE}$  must return to the high state for a minimum recovery time (t<sub>WR</sub>) before another cycle can be initiated. The  $\overline{OE}$  control signal should be kept inactive (high) during write cycles to avoid bus contention. However, if the output drivers are enabled ( $\overline{CE}$  and  $\overline{OE}$  active), then  $\overline{WE}$ will disable the outputs in topw from its falling edge.

## **DATA-RETENTION MODE**

The DS1249W provides full functional capability for  $V_{CC}$  greater than 3.0 volts and write protects by 2.8V. Data is maintained in the absence of  $V_{CC}$  without any additional support circuitry. The nonvolatile static RAMs constantly monitor  $V_{CC}$ . Should the supply voltage decay, the NV SRAMs automatically write protects themselves, all inputs become "don't care," and all outputs become high impedance. As  $V_{CC}$  falls below approximately 2.5V, a power-switching circuit connects the lithium energy source to RAM to retain data. During power-up, when  $V_{CC}$  rises above approximately 2.5V, the power-switching circuit connects external  $V_{CC}$  to the RAM and disconnects the lithium energy source. Normal RAM operation can resume after  $V_{CC}$  exceeds 3.0V.

## FRESHNESS SEAL

Each DS1249 device is shipped from Maxim with its lithium energy source disconnected, guaranteeing full energy capacity. When  $V_{CC}$  is first applied at a level greater than  $V_{TP}$ , the lithium energy source is enabled for battery backup operation.

## **ABSOLUTE MAXIMUM RATINGS**

Voltage on Any Pin Relative to Ground Operating Temperature Range Commercial: Industrial: Storage Temperature Range Lead Temperature (soldering, 10s) **Note:** EDIP is wave or hand soldered only.

0°C to +70°C -40°C to +85°C -40°C to +85°C +260°C

-0.3V to +4.6V

This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operation sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods of time may affect reliability.

| RECOMMENDED DC OPERATING CONDITIONS |                 |     |     | (T              | A: See N | Note 10) |
|-------------------------------------|-----------------|-----|-----|-----------------|----------|----------|
| PARAMETER SYMBOL MIN TYP            |                 |     |     |                 | UNITS    | NOTES    |
| Power-Supply Voltage                | V <sub>CC</sub> | 3.0 | 3.3 | 3.6             | V        |          |
| Logic 1                             | V <sub>IH</sub> | 2.2 |     | V <sub>CC</sub> | V        |          |
| Logic 0                             | V <sub>IL</sub> | 0.0 |     | +0.4            | V        |          |

### **DC ELECTRICAL CHARACTERISTICS**

 $(T_A: See Note 10; V_{CC} = 3.3V \pm 0.3V)$ 

| PARAMETER   | SYMBOL            | MIN  | ТҮР | MAX  | UNITS | NOTES |
|---|-------------------|------|-----|------|-------|-------|
| Input Leakage Current                                     | I <sub>IL</sub>   | -2.0 |     | +2.0 | μΑ    |       |
| I/O Leakage Current $\overline{CE} \ge V_{IH} \le V_{CC}$ | I <sub>IO</sub>   | -2.0 |     | +2.0 | μΑ    |       |
| Output Current at 2.2V                                    | I <sub>OH</sub>   | -1.0 |     |      | mA    |       |
| Output Current at 0.4V                                    | I <sub>OL</sub>   | 2.0  |     |      | mA    |       |
| Standby Current $\overline{CE} = 2.2V$                    | I <sub>CCS1</sub> |      | 150 | 250  | μA    |       |
| Standby Current $\overline{CE} = V_{CC} - 0.2V$           | I <sub>CCS2</sub> |      | 100 | 150  | μΑ    |       |
| Operating Current   | I <sub>CCO1</sub> |      |     | 50   | mA    |       |
| Write Protection Voltage                                  | V <sub>TP</sub>   | 2.8  | 2.9 | 3.0  | V     |       |

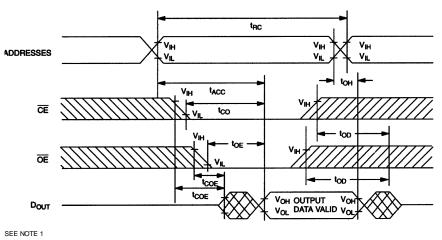
### CAPACITANCE

 $(T_A = +25^{\circ}C)$ 

|                          |                  |     |     |     |       | ,     |
|--------------------------|------------------|-----|-----|-----|-------|-------|
| PARAMETER                | SYMBOL           | MIN | TYP | MAX | UNITS | NOTES |
| Input Capacitance        | C <sub>IN</sub>  |     | 10  | 20  | pF    |       |
| Input/Output Capacitance | C <sub>I/O</sub> |     | 10  | 20  | pF    |       |

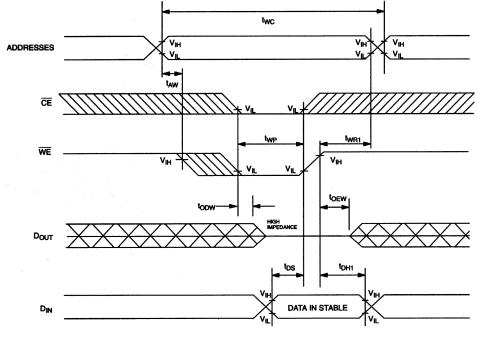
| AC ELECTRICAL CHARAC  | IERISTICS        | •     | See Note 10 | $V_{\rm CC} = 3$ | $5.3V \pm 0.$ |  |
|---|------------------|-------|-------------|------------------|---------------|--|
| PARAMETER   | SYMBOL           | DS124 | 9W-100      | UNITS            | NOTES         |  |
| IARANIETER  | SIMDUL           | MIN   | MAX         | UNIIS            | NOILS         |  |
| Read Cycle Time   | t <sub>RC</sub>  | 100   |             | ns               |               |  |
| Access Time   | t <sub>ACC</sub> |       | 100         | ns               |               |  |
| $\overline{\text{OE}}$ to Output Valid                            | t <sub>OE</sub>  |       | 50          | ns               |               |  |
| CE to Output Valid  | t <sub>CO</sub>  |       | 100         | ns               |               |  |
| $\overline{\text{OE}}$ or $\overline{\text{CE}}$ to Output Active | t <sub>COE</sub> | 5     |             | ns               | 5             |  |
| Output High-Z from Deselection                                    | t <sub>OD</sub>  |       | 35          | ns               | 5             |  |
| Output Hold from Address Change                                   | t <sub>OH</sub>  | 5     |             | ns               |               |  |
| Write Cycle Time  | t <sub>WC</sub>  | 100   |             | ns               |               |  |
| Write Pulse Width   | t <sub>WP</sub>  | 75    |             | ns               | 3             |  |
| Address Setup Time  | t <sub>AW</sub>  | 0     |             | ns               |               |  |
| Write Recovery Time   | t <sub>WR1</sub> | 5     |             | ns               | 12            |  |
| white Recovery Thile  | t <sub>WR2</sub> | 20    |             | ns               | 13            |  |
| Output High-Z from $\overline{WE}$                                | t <sub>ODW</sub> |       | 35          | ns               | 5             |  |
| Output Active from $\overline{WE}$                                | t <sub>OEW</sub> | 5     |             | ns               | 5             |  |
| Data Setup Time   | t <sub>DS</sub>  | 40    |             | ns               | 4             |  |
| Data Hold Time  | t <sub>DH1</sub> | 0     |             | ns               | 12            |  |
|   | t <sub>DH2</sub> | 20    |             | ns               | 13            |  |

## **READ CYCLE**



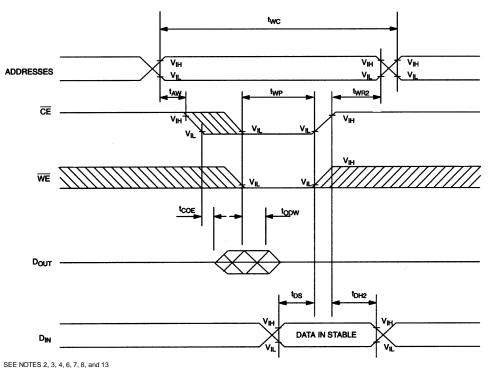
Downloaded from  $\underline{\text{Elcodis.com}}$  electronic components distributor

## WRITE CYCLE 1

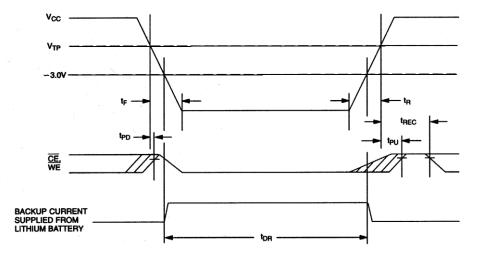


SEE NOTES 2, 3, 4, 6, 7, 8, and 12

## WRITE CYCLE 2



## **POWER-DOWN/POWER-UP CONDITION**



SEE NOTE 11

| POWER-DOWN/POWER-UP TIMING   |                  |     |  | ۲)  | A: See N | Note 10) |
|--|------------------|-----|--|-----|----------|----------|
| PARAMETER SYMBOL MIN TYP   |                  |     |  | MAX | UNITS    | NOTES    |
| $V_{CC}$ Fail Detect to $\overline{CE}~$ and $\overline{WE}~$ Inactive | t <sub>PD</sub>  |     |  | 1.5 | μs       | 11       |
| $V_{CC}$ Slew from $V_{TP}$ to 0V                                      | t <sub>F</sub>   | 150 |  |     | μs       |          |
| $V_{CC}$ Slew from 0V to $V_{TP}$                                      | t <sub>R</sub>   | 150 |  |     | μs       |          |
| $V_{CC}$ Valid to $\overline{CE}$ and $\overline{WE}$ Inactive         | t <sub>PU</sub>  |     |  | 2   | ms       |          |
| V <sub>CC</sub> Valid to End of Write Protection                       | t <sub>REC</sub> |     |  | 125 | ms       |          |

|                              |                 |     |     |     | (T <sub>A</sub> = | = +25°C) |
|------------------------------|-----------------|-----|-----|-----|-------------------|----------|
| PARAMETER                    | SYMBOL          | MIN | ТҮР | MAX | UNITS             | NOTES    |
| Expected Data-Retention Time | t <sub>DR</sub> | 10  |     |     | years             | 9        |

### WARNING:

E

Under no circumstance are negative undershoots, of any amplitude, allowed when device is in battery backup mode.

### NOTES:

- 1.  $\overline{\text{WE}}$  is high for a read cycle.
- 2.  $\overline{OE} = V_{IH}$  or  $V_{IL}$ . If  $\overline{OE} = V_{IH}$  during write cycle, the output buffers remain in a high impedance state.
- 3.  $t_{WP}$  is specified as the logical AND of  $\overline{CE}$  and  $\overline{WE}$ .  $t_{WP}$  is measured from the latter of  $\overline{CE}$  or  $\overline{WE}$  going low to the earlier of  $\overline{CE}$  or  $\overline{WE}$  going high.
- 4.  $t_{DS}$  is measured from the earlier of  $\overline{CE}$  or  $\overline{WE}$  going high.
- 5. These parameters are sampled with a 5pF load and are not 100% tested.
- 6. If the  $\overline{CE}$  low transition occurs simultaneously with or latter than the  $\overline{WE}$  low transition in Write Cycle 1, the output buffers remain in a high-impedance state during this period.

- 7. If the  $\overline{CE}$  high transition occurs prior to, or simultaneously with, the  $\overline{WE}$  high transition, the output buffers remain in a high-impedance state during this period.
- 8. If  $\overline{WE}$  is low or the  $\overline{WE}$  low transition occurs prior to, or simultaneously with, the  $\overline{CE}$  low transition, the output buffers remain in a high-impedance state during this period.
- 9. Each DS1249W has a built-in switch that disconnects the lithium source until  $V_{CC}$  is first applied by the user. The expected  $t_{DR}$  is defined as accumulative time in the absence of  $V_{CC}$  starting from the time power is first applied by the user.
- 10. All AC and DC electrical characteristics are valid over the full operating temperature range. For commercial products, this range is 0°C to +70°C. For industrial products (IND), this range is -40°C to +85°C.
- 11. In a power-down condition, the voltage on any pin may not exceed the voltage on  $V_{CC}$ .
- 12.  $t_{WR1}$  and  $t_{DH1}$  are measured from  $\overline{WE}$  going high.
- 13.  $t_{WR2}$  and  $t_{DH2}$  are measured from  $\overline{CE}$  going high.
- 14. DS1249 modules are recognized by Underwriters Laboratories (UL) under file E99151.

### **DC TEST CONDITIONS**

Outputs open Cycle = 200ns for operating current All voltages are referenced to ground

### **AC TEST CONDITIONS**

Output Load: 100pF + 1TTL Gate Input Pulse Levels: 0 to 2.7V Timing Measurement Reference Levels Input: 1.5V Output: 1.5V Input Pulse Rise and Fall Times: 5ns

### **ORDERING INFORMATION**

| PART            | TEMP RANGE                         | SUPPLY<br>TOLERANCE | PIN-PACKAGE | SPEED GRADE<br>(ns) |
|-----------------|------------------------------------|---------------------|-------------|---------------------|
| DS1249W-100#    | $0^{\circ}$ C to $+70^{\circ}$ C   | $3.3V \pm 0.3V$     | 32 740 EDIP | 100                 |
| DS1249W-100IND# | $-40^{\circ}$ C to $+85^{\circ}$ C | $3.3V \pm 0.3V$     | 32 740 EDIP | 100                 |

#Denotes a RoHS-compliant device that may include lead(Pb) that is exempt under the RoHS requirements.

## **PACKAGE INFORMATION**

For the latest package outline information and land patterns, go to <u>www.maxim-ic.com/packages</u>. Note that a "+", "#", or "-" in the package code indicates RoHS status only. Package drawings may show a different suffix character, but the drawing pertains to the package regardless of RoHS status.

| PACKAGE TYPE | PACKAGE CODE | OUTLINE NO.    | LAND PATTERN NO. |
|--------------|--------------|----------------|------------------|
| 32 EDIP      | MDT32#7      | <u>21-0245</u> | —                |

## **REVISION HISTORY**

| REVISION<br>DATE | DESCRIPTION   | PAGES<br>CHANGED |
|------------------|---|------------------|
| 11/10            | Updated the storage information, soldering temperature, and lead<br>temperature information in the <i>Absolute Maximum Ratings</i> section;<br>removed the -150 MIN/MAX information from the <i>AC Electrical</i><br><i>Characteristics</i> table; updated the <i>Ordering Information</i> table (removed -<br>150 parts and leaded -100 parts); added the <i>Package Information</i> table | 1, 3, 4, 7       |